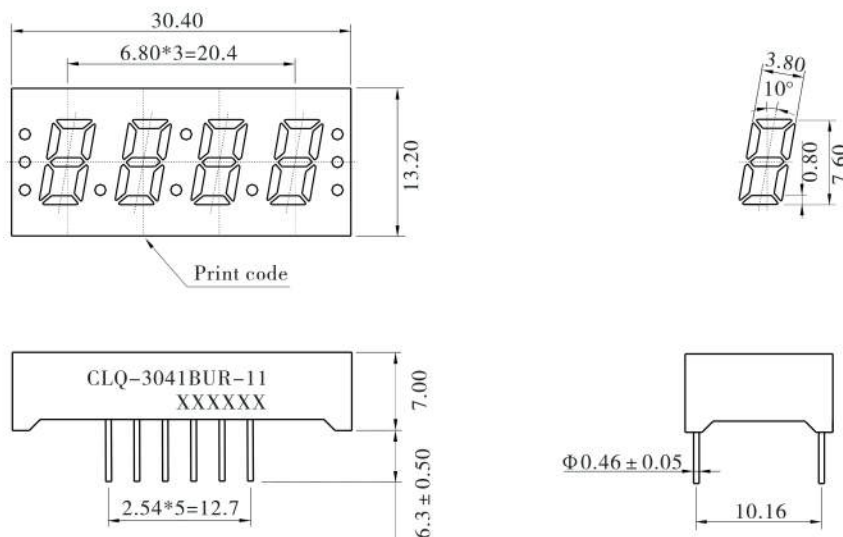


Descriptions

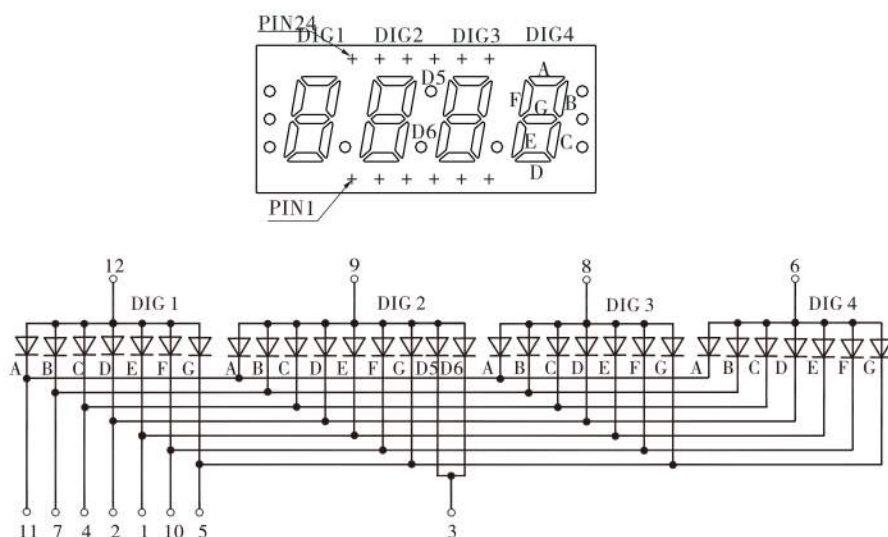
1. Emitting Color: Ultra Red
2. Lens Color: White Diffuseb
3. Surface Ink Color : Black
4. Dice Material: AlGaInP/GaAs

Outline Drawing



Tolerance is $\pm 0.25\text{mm}$ unless otherwise noted, Unit=mm
Pin bending $\leq \text{length} \times 1\%$

Internal Circuit Diagram(C.A.)



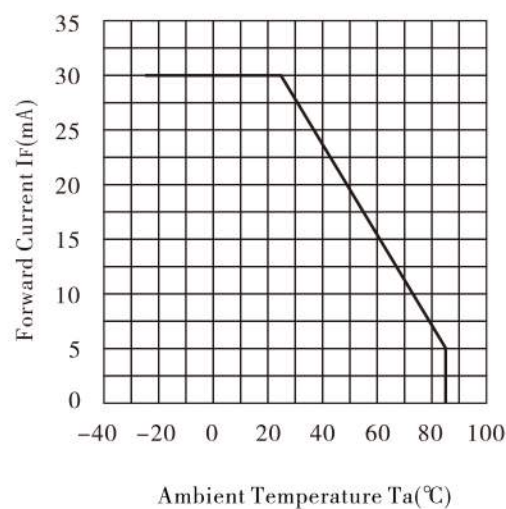
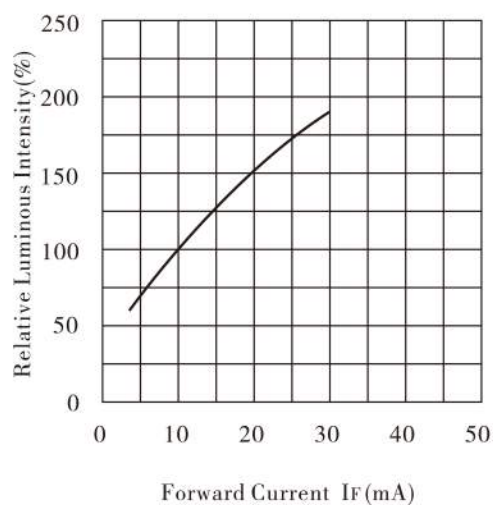
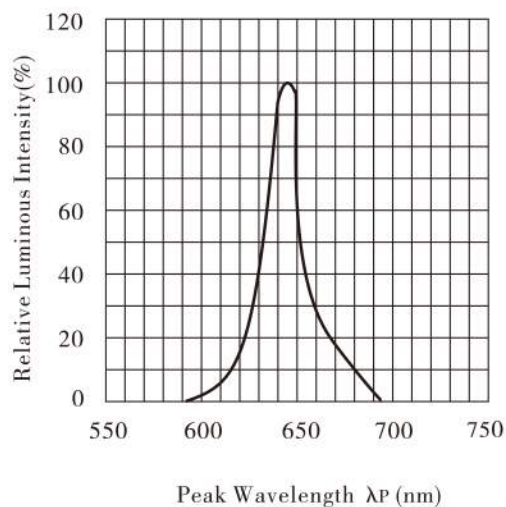
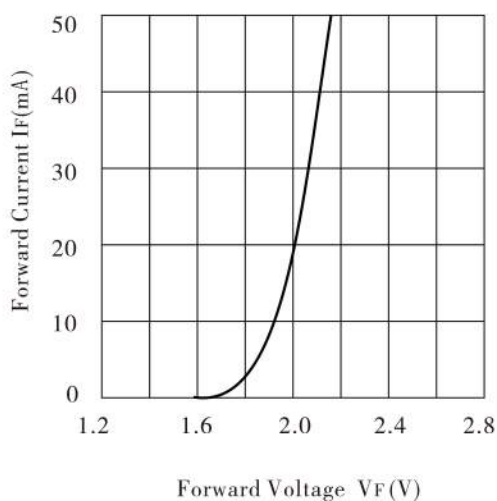
Electrical Optical Characteristics(Ta=25℃)

Parameter	Symbol	Ultra Red			Unit	Test Condition
		Min	Typ	Max		
Forward Voltage	V _F	---	2.0	2.4	V	IF=20mA
Luminous Intensity	I _V	2.5	5.0	---	mcd	IF=10mA
Peak Wavelength	λ _P	---	645	---	nm	IF=20mA
Dominant Wavelength	λ _d	---	640	---	nm	IF=20mA
Spectral Line half-width	Δλ	---	20	---	nm	IF=20mA
Reverse Leakage Current	I _R	---	---	50	μA	VR=5V

Absolute Maximum Parameters(Ta=25℃)

Parameter	Symbol	Condition	Rating	Unit
Power Dissipation	P _D	---	80	mW
Reverse Voltage	V _R	---	5	V
Forward Average Current	I _F	---	30	mA
Temperature Coefficient	I/C	---	0.33	mA/℃
Pulse Current	IFP	Duty=1/10,1kHz	100	mA
Operating Temperature Range	Topr	---	-25 ~ +85	℃
Storage Temperature Range	Tstg	---	-30 ~ +100	℃
Soldering Condition	Tsd	---	260℃/5sec	℃

Typical Electro/Optical Characteristic Curves(Ta=25°C)



Reliability Test Conditions

Test Item	Test Condition	Result	Judgment Criteria
Consecutive operating life test	IF=20mA, T=25℃, t=168h	0/10	Forward Voltage VF(V)= Upper Limit × 1.2 Reverse Leakage Current IR(μ A)=Upper Limit × 2.0 Luminous Intensity IV (mcd)=Lower Limit × 0.7
High temperature storage life test	T=100℃, t=168h	0/10	
Low temperature storage life test	T=-25℃, t=168h	0/10	
High temperature humidity storage life test	T=85 ± 2℃, RH=85% ± 3, t=168h	0/10	
Temperature cycle test	-25℃~25℃~100℃ 30min 5min 30min 10cycles	0/10	
Thermal shock test	100℃ 0℃ 5min 5min 20cycles	0/10	
Soldering heat test	T=260 ± 5℃, t=10s ± 1s	0/10	
Solderability test	T=235 ± 5℃, t=5s ± 0.5s	0/10	Steeped Part ≥ 95%
Fall test	h=100cm, 50times	0/10	Surface Appearance Photoelectric Properties Intact
Terminal strength test	W=9.8N, t=30 ± 5s	0/10	
Lead bending test	W=4.9N, 2times	0/10	